

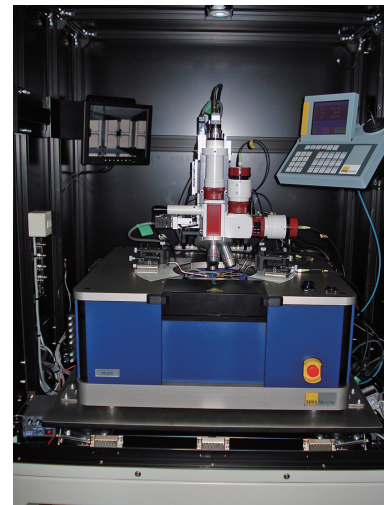
WAFER LEVEL OPTICAL CHARACTERISTIC MEASUREMENT SYSTEM FOR LIGHT RECEIVING DEVICE

Wafer level testing of optical characteristic for light receiving device in combination with manual/semi automatic probe system

Wafer level optical characteristic measurement system for light receiving device is the system that analyzes electrical and optical characteristics of various light receiving device such as photodiodes and photosensors at wafer level. In addition to electrical characteristics measurement, optical characteristics can be measured at wafer level by introducing measurement light. By combining probe systems for semiconductor failure analysis, such as semi-automatic/manual probers, with our high-performance optical measurement optics for prober **M-Scope type I/PFW**, measurement light sources, measuring instruments, etc. various characteristics are measured under wafer level. In addition, it can be used for automatic measurement of mass-produced devices in combination with the semi-automatic prober.

[Features]

- Wafer level measurement of various electrical and optical characteristics of photo detectors such as photodiodes and photo sensors in combination with semi-automatic/manual prober.
- Achieves automation of various measurements combining with the semi-automatic prober system. Applicable from off-line measurement of individual elements to in-line measurement.
- High-performance optical measurement optics for prober **M-Scope type I/PFW**
 - High functional optical measurement optics designed for wafer level optical measurement.
- Prober interlocking optical measurement software **Optometrics customized version for PD**
 - Semi-automatic prober control and analysis automation, collection of measured data, unified management of measurement types and measurement recipes, etc.



[Prober interlocking optical characteristic measurement software “Optometrics Customized Version for PD”]

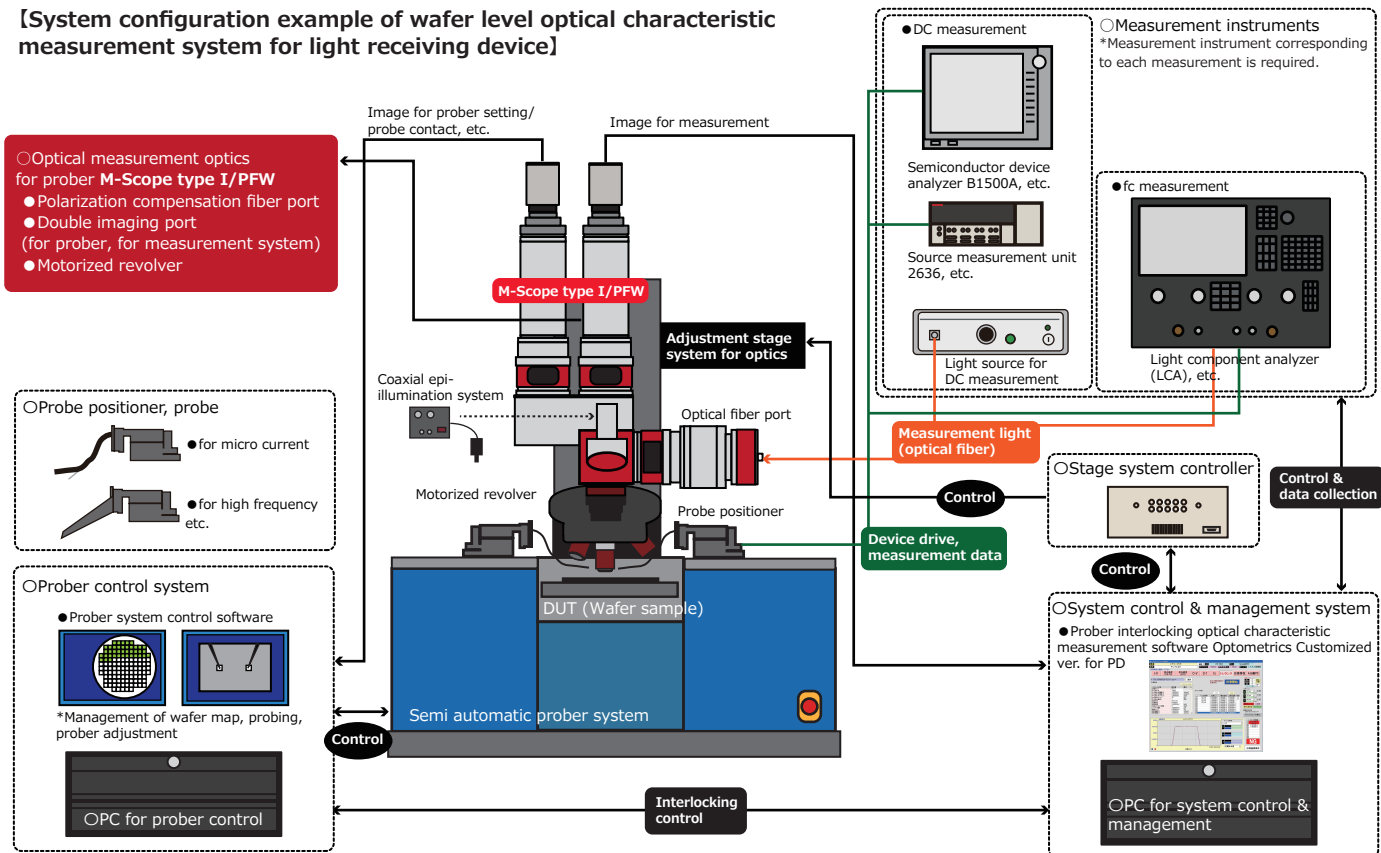


This software has been developed for wafer-level optical element measurement, which automates analysis by controlling and linking the semi-auto prober, integrates electrical and optical characteristic data collection, and manages measurement types and measurement recipes. A wide range of support is available, from offline measurement to in-line automatic measurement. The measurement item customizes the software according to the measurement target, measurement content, measuring instrument used, measurement procedure and operation.

《Typical measurement items》

- Electric and optical characteristic of light receiving device such as PD, optical sensor
 - I-V characteristic, photosensitivity, dark current, capacitance, cutoff frequency, rise time, tolerance, crosstalk, etc.
 - * Measurement instrument corresponding to each measurement is required.

[System configuration example of wafer level optical characteristic measurement system for light receiving device]



*We will propose system with various configurations and specifications depending on the measurement sample, specifications, operating method, and budget.